

TEST REPORT

FCC ID: 2ALGRPLX-V70

Product: Cell phone signal booster

Model No.: PLX-V70

Additional Model No.: PLX-WV70, PLX-BV70 ,PLX-WV70A,PLX-BV70A

Trade Mark: N/A

Report No.: TCT170309E018

Issued Date: Apr. 06, 2017

Issued for:

Shenzhen Fuzhixing Electronics Co., Ltd.

5/F, Block C, Penglongpan Hi-technology Park, Dafu Ind. Zone, Guanlan,
Longhua New Dist., Shenzhen, Guangdong, China

Issued By:

Shenzhen Tongce Testing Lab.

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Hotline: 400-6611-140 Tel: 86-755-27673339 Fax: 86-755-27673332 http://www.tct-lab.com





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1. Test Certification

Product:	Cell phone signal booster	
Model No.:	PLX-V70	(,C
Additional Model:	PLX-WV70, PLX-BV70 ,PLX-WV70A,PLX-BV70A	
Applicant:	Shenzhen Fuzhixing Electronics Co., Ltd.	
Address:	5/F, Block C, Penglongpan Hi-technology Park, Dafu Ind. Zone, Guanlan, Longhua New Dist., Shenzhen, Guangdong, China	
Manufacturer:	Shenzhen Fuzhixing Electronics Co., Ltd.	(60
Address:	5/F, Block C, Penglongpan Hi-technology Park, Dafu Ind. Zone, Guanlan, Longhua New Dist., Shenzhen, Guangdong, China	
Date of Test:	Mar. 21 – Mar. 28, 2017	
Applicable Standards:	FCC CFR Title 47 Part 20.21	

The above equipment has been tested by Shenzhen Tongce Testing Lab. and found compliance with the requirements set forth in the technical standards mentioned above. The results of testing in this report apply only to the product/system, which was tested. Other similar equipment will not necessarily produce the same results due to production tolerance and measurement uncertainties.

	(,C))			
Tested By:	I'm Wang	Date:	Apr. 06, 2017	
(C)	Jin Wang	Q	<u>(c')</u>	
Reviewed By:	Longhon	Date:	Apr. 06, 2017	
	Joe Zhou		(c)	
Approved By:	Tomsin	Date:	Apr. 06, 2017	
	Tomsin			





2. Test Result Summary

Requirement	CFR 47 Section	Result
Authorized Frequency Band Verification Test	§20.21(e)(3)	PASS
Maximum Power Measurement Procedure	§2.1046/20.21(e)(8)(i)(D)	PASS
Maximum Booster Gain Computation	§20.21(e)(8)(i)(B)	PASS
Intermodulation Product	§20.21(e)(8)(i)(F)	PASS
Out of Band Emissions	§20.21(e)(8)(i)(E)	PASS
Conducted Spurious Emission	§2.1051/§27	PASS
Noise Limit Procedure Variable Noise Variable Noise Timing	§20.21(e)(8)(i)(A)(2)(i) §20.21(e)(8)(i)(A)(1) §20.21(e)(8)(i)(H)	PASS
Uplink inactivity	§20.21(e)(8)(i)(I)	PASS
Variable Booster Gain Variable Uplink Gain Timing	§20.21(e)(8)(i)(C) (1), (2)(i) §20.21(e)(8)(i)(H)	PASS
Occupied Band Width	§2.1049/§27	PASS
Anti-Oscillation	§20.21(e)(8)(ii)(A)	PASS
Radiated Spurious Emission	§2.1053/§27	PASS
Spectrum Block Filter	N/A	N/A

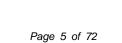
Note:

- 1. PASS: Test item meets the requirement.
- 2. Fail: Test item does not meet the requirement.
- 3. N/A: Test case does not apply to the test object.
- 4. The test result judgment is decided by the limit of test standard.



3. EUT Description

Product Name:	Cell phone signal booster
Model :	PLX-V70
Additional Model:	PLX-WV70, PLX-BV70 ,PLX-WV70A,PLX-BV70A
Trade Mark:	N/A
Operation Frequency:	Band 13 Uplink: 776 MHz -787MHz, Downlink: 746 MHz -757MHz
Emission Designator:	LTE(G7D)
AGC Level:	Uplink:-45.00 Downlink:-56.00
Gain:	Uplink: 60 ± 2 dB Downlink: 62 ± 2 dB
Conducted Output Power:	Uplink:18.33dBm Downlink:7.95dBm
Max. Antenna Gain:	Uplink:8.1dBi Downlink:6.6 dBi
EIRP:	Uplink:26.43dBm Downlink:14.55dBm
FCC Classification:	B2W/Wideband Consumer Booster(CMRS)
Power Supply:	DC 5V from adapter
Remark:	All models above are identical in interior structure, electrical circuits and components, just model names and surface are different for the marketing requirement.



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4. Genera Information

4.1. Test environment

Operating Environment:	
Temperature:	25.0 °C
Humidity:	56 % RH
Atmospheric Pressure:	1010 mbar

4.2. Description of Support Units

The EUT has been tested as an independent unit together with other necessary accessories or support units. The following support units or accessories were used to form a representative test configuration during the tests.

Equipment	Model No.	Serial No.	FCC ID	Trade Name
AC Adapter	FZX-05-25	E	1	Phonelex





5. Facilities and Accreditations

5.1. Facilities

The test facility is recognized, certified, or accredited by the following organizations:

• FCC - Registration No.: 572331

Shenzhen Tongce Testing Lab

The 3m Semi-anechoic chamber has been registered and fully described in a report with the (FCC) Federal Communications Commission. The acceptance letter from the FCC is maintained in our files.

• IC - Registration No.: 10668A-1

The 3m Semi-anechoic chamber of Shenzhen TCT Testing Technology Co., Ltd. has been registered by Certification and Engineering Bureau of Industry Canada for radio equipment testing

CNAS - Registration No.: CNAS L6165
 Shenzhen TCT Testing Technology Co., Ltd. is accredited to ISO/IEC 17025:2005
 General Requirements for the Competence of Testing and Calibration laboratories for the competence of testing. The Registration No. is CNAS L6165.

5.2. Location

Shenzhen Tongce Testing Lab

Address: 1F, Leinuo Watch Building, Fuyong Town, Baoan Dist, Shenzhen, China

Tel: 86-755-36638142

5.3. Measurement Uncertainty

The reported uncertainty of measurement $y \pm U$, where expended uncertainty U is based on a standard uncertainty multiplied by a coverage factor of k=2, providing a level of confidence of approximately 95 %.

No.	Item	MU
1	Conducted Emission	±2.56dB
2	RF power, conducted	±0.12dB
3	Spurious emissions, conducted	±0.11dB
4	All emissions, radiated(<1G)	±3.92dB
5	All emissions, radiated(>1G)	±4.28dB
6	Temperature	±0.1°C
7	Humidity	±1.0%

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6. Test Results and Measurement Data

6.1. Authorized Frequency Band Verification

6.1.1. Test Specification

Test Requirement:	FCC Part20 Section 20.21(e)(3)		
Test Method:	935210 D03 Signal Booster Measurements v04		
Limit	Uplink: 776 MHz ~ 787 MHz Downlink: 746MHz ~ 757MHz		
Test Setup:	RF Attenuator (if required) Spectrum Analyzer Signal Generator		
Test Procedure:	 935210 D03 Signal Booster Measurement v02r01 a) Connect the EUT to the test equipment as shown in Figure 1. Begin with the uplink output (donor) port connected to the spectrum analyzer. b) Set the spectrum analyzer resolution bandwidth (RBW) for 100 kHz with the video bandwidth (VBW) ≥ 3 x the RBW, using a PEAK detector with the MAX HOLD function. c) Set the center frequency of the spectrum analyzer to the center of the operational band under test with a span of 1 MHz. d) Set the signal generator for CW mode and tune to the center frequency of the operational band under test. e) Set the initial signal generator power to a level that is at least 6 dB below the AGC level specified by the manufacturer. f) Slowly increase the signal generator power level until the output signal reaches the AGC operational level. g) Reduce the signal generator power to a level that is 3 dB below the level noted above, then manually reset the EUT (e.g., cycle ac/dc power). h) Reset the spectrum analyzer span to 2xthe width of the CMRS band under test. Adjust the tuned frequency of the signal generator to sweep 2xthe width of the CMRS band using the sweep function. The AGC must be deactivated throughout the entire sweep. i) Using three markers, identify the CMRS band edges and the frequency with the highest power. Affirm that the values of all markers are visible on the display of the spectrum analyzer (e.g., marker table set to on). j) Capture the spectrum analyzer trace for inclusion in the test report. k) Repeat 7.1c) to 7.1j) for all operational uplink and downlink bands. 		
Test Result:	bands. PASS		
rest resuit.	FAGG		



6.1.2. Test Instruments

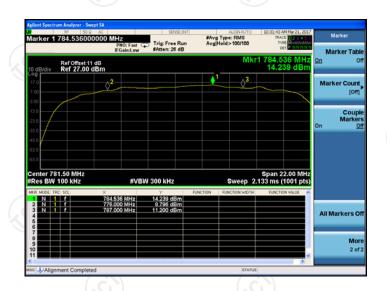
Equipment	Manufactur er	Model	Serial Number	Calibration Date	Calibration Due
Signal Generator	Agilent	N5182	MY4707028 2	Aug. 15, 2016	Aug. 11, 2017
Spectrum Analyzer	Agilent	N9020A	MY4910006 0	Aug. 15, 2016	Aug. 11, 2017
Attenuation	AF115A-09- 34	JFW	907763	Aug. 15, 2016	Aug. 11, 2017

Note: The calibration interval of the above test instruments is 12 months and the calibrations are traceable to international system unit (SI).

6.1.3. Test data

Plot

Uplink



Downlink





6.2. Maximum Power

6.2.1. Test Specification

Test Requirement:	FCC Part 20.21 (e)(8)(i)(B); FCC Part 20.21 (e)(8)(i)(D)			
Test Method:	KDB935210 D03 Signal Booster Measurement v04			
Limit:	Uplink: Upper / 1 W (30 dBm), Lower / 50 mW (17 dBm) Downlink: Upper / 50 mW (17 dBm)			
Test Setup:	Spectrum Analyzer RF Attenuator (if required) EUT Signal Generator			
Test Procedure:	a) Connect the EUT to the test equipment as shown in Set-Up. Begin with the uplink output (donor port) connected to the spectrum analyzer. b) Configure the signal generator and spectrum analyzer for operation on the frequency determined in Frequency Band with the highest power level, but with the center frequency of the signal no closer than 2.5 MHz from the band edge. The spectrum analyzer span shall be set to at least 10 MHz. c) Set the initial signal generator power to a level well below that which causes AGC control. d) Slowly increase the signal generator power level until the output signal reaches the AGC operational limit (from observation of signal behavior on the spectrum analyzer; e.g., no further increase in output power as input power is increased). e) Reduce power sufficiently on the signal generator to ensure that the AGC is not controlling the power output. f) Slowly increase the signal generator power to a level just below (within 0.5 dB of) the AGC limit without triggering the AGC. Note the signal generator power level as (Pin). g) Measure the output power (Pout) with the spectrum analyzer as follows. h) Set RBW = 100 kHz for AWGN signal type and 300 kHz for CW or GSM signal type i) Set VBW ≥ 3X RBW j) Select either the BURST POWER or CHANNEL POWER measurement tool, as required for each signal type. The channel power integration bandwidth shall be 99% occupied bandwidth (4.1 MHz). k) Select the RMS (power averaging) detector. l) Ensure that the number of measurement points per sweep ≥ (2 x span)/RBW (Note: This requirement does not apply for BURST power measurement mode). m) Set sweep time = auto couple, or as necessary (but no less than auto couple value). n) Trace average at least 100 traces in power averaging (i.e., RMS) mode. o) Record the measured power level as Pout with one set of results for the AWGN input stimulus. p) Repeat the procedure for each operational uplink and downlink frequency band supported by the booster.			
Test Result:	PASS			

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6.2.2. Test Instruments

Equipment	Manufactur er	Model	Serial Number	Calibration Date	Calibration Due
Signal Generator	Agilent	N5182	MY4707028 2	Aug. 15, 2016	Aug. 11, 2017
Spectrum Analyzer	Agilent	N9020A	MY4910006 0	Aug. 15, 2016	Aug. 11, 2017
Attenuation	AF115A-09- 34	JFW	907763	Aug. 15, 2016	Aug. 11, 2017

Note: The calibration interval of the above test instruments is 12 months and the calibrations are traceable to international system unit (SI).

6.2.3. Test Data

Pre AGC							
Pulse GSM				4.1MHz AWGN	ı		
Frequency (MHz)	Input (dBm)	Output (dBm)	*Gain (dB)	Input (dBm)	Output (dBm)	*Gain (dB)	
UL 776-787	-44.00	17.93	61.93	-41.00	17.37	61.37	
DL 746-757	-56.00	7.56	63.56	-56.00	7.25	63.25	

*Fixed Booster maximum gain shall not exceed 6.5 dB + 20 Log10 (Frequency), where Frequency is the uplink mid-band frequency of the supported spectrum bands in MHz.

Pulse GSM					Conducted	and EIRP
Frequency (MHz)	Output Power (dBm)	Ant Gain (dBi)	Cable Loss (dB)	EIRP (dBm)	Limit Min (dBm)	Limit Max (dBm)
UL 776-787	17.93	10.00	1.90	26.03	17	30
DL 746-757	7.56	7.00	0.40	15.16	N/A	17

4.1MHz AWGN					Conducted	d and EIRP
Frequency (MHz)	Output Power (dBm)	Ant Gain (dBi)	Cable Loss (dB)	EIRP (dBm)	Limit Min (dBm)	Limit Max (dBm)
UL 776-787	17.37	10.00	1.90	25.47	17	30
DL 746-757	7.25	7.00	0.40	13.85	N/A	17



Section 5.5 Power							
Pulse GSM				4.1MHz AWGN			
Frequency (MHz)	Input (dBm)	Output (dBm)	*Gain (dB)	Input (dBm)	Output (dBm)	*Gain (dB)	
UL 776-787	-40.00	18.33	58.33	-40.00	17.94	57.94	
DL 746-757	-50.00	7.95	57.95	-50.00	7.69	57.69	

Note: The booster went into Transmitter off mode at Max input power of -20dBm (DL). Results presented on the above table are at 1 dB below the Transmit off RF input level. This table it is for reference only.

	Pulse GSM	4.1MHz GSM	Limit (dB)	
UL gain vs DL gain	1.63	1.88	9.0	



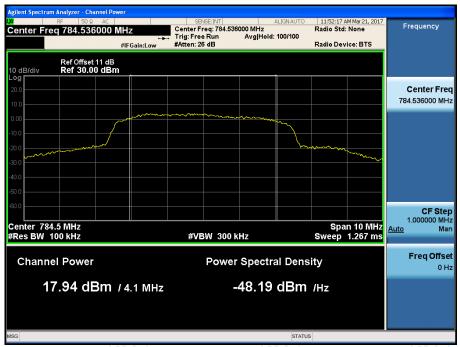


Plot

AWGN, UL



UL 776-787MHz AWGN



UL_776-787MHz_AWGN_Max



AWGN, DL



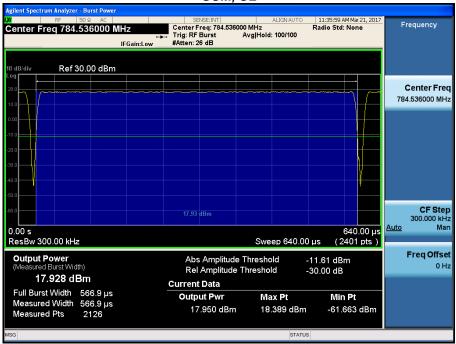
DL_746-757MHz_AWGN



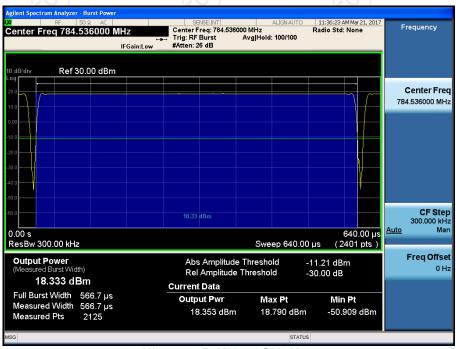
DL_746-757MHz_AWGN_Max



GSM, UL



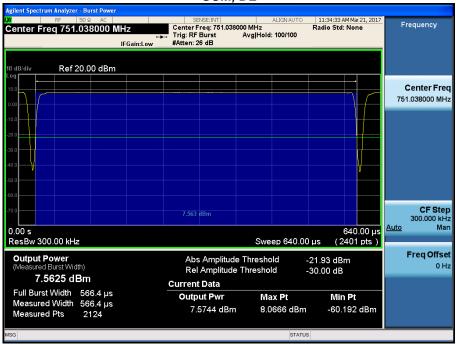
UL_746-757MHz_GSM



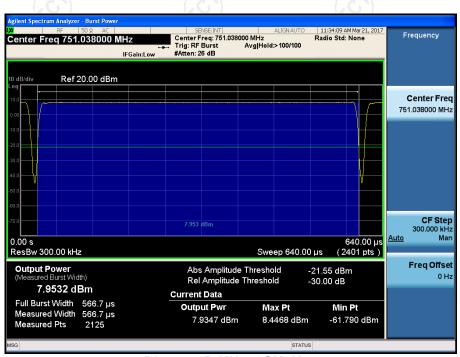
UL_746-757MHz_GSM_Max



GSM, DL



DL_746-757MHz_GSM



DL_746-757MHz_GSM_Max



TESTING CENTRE TECHNOLOGY Report No.: TCT170309E018

6.3. Intermodulation Product

6.3.1. Test Specification

Test Requirement:	FCC Part20 Section 20.21(e)(8)(i)(F)					
Test Method:	KDB935210 D03 Signal Booster Measurement v04					
Limit:	-19dBm					
Test Setup:	Spectrum Analyzer Figure 2 — Intermodulation	Signal Generator #1 Signal Generator #2 In product instrumentation test setup	biner			
Test Procedure:	a) Connect the signal is Set-Up. Begin with the analyzer. b) Set the spectrum ar c) Set the VBW ≥ 3 3 d) Select the RMS dete e) Set the spectrum ar supported operational f) Set the span to 5 Mig) Configure the two signerator 1 tuned 300 frequency and generate band center frequency h) Set the signal generate into the RF combiner is i) Increase the signal generate into the RF combiner is i) Increase the signal generate band center frequency h) Set the signal generate into the RF combiner is ii) Increase the signal generate into the RF combiner is ii) Increase the signal generate into the RF combiner is ii) Increase the signal in the EUT begins AGC at any exist), are below the j) Utilize the trace aver wait for the trace to state amplitude intermodulate k) Record the maximum that is observed. l) Capture the spectrum report. m) Repeat steps e) to bands. Note: If using a single that intermodulation prof the generator. n) Increase the signal gabove the AGC thresh	pooster to the test equipment uplink output connected to the RBW. It	to the spectrum of the center of the peration with all band center the the operational the power from each the RF output. The products (if the band before the adulation products (if the band before the adulation products (if the highest the amplitude level the perational the operational the operational the outputs, ensure all steps to 10 dB			
Test Result:	PASS	with the intermodulation				



6.3.2. Test Instruments

Equipment	Manufactur er	Model	Serial Number	Calibration Date	Calibration Due
Signal Generator	Agilent	E4421B	GB39340839	Aug. 15, 2016	Aug. 11, 2017
Signal Generator	Agilent	N5182	MY4707028 2	Aug. 15, 2016	Aug. 11, 2017
Spectrum Analyzer	Agilent	N9020A	MY4910006 0	Aug. 15, 2016	Aug. 11, 2017
RF Combiner	SUNVNDN	SUD-CS 0800	16230009	Aug. 15, 2016	Aug. 11, 2017
Attenuation	AF115A-09- 34	JFW	907763	Aug. 15, 2016	Aug. 11, 2017

Note: The calibration interval of the above test instruments is 12 months and the calibrations are traceable to international system unit (SI).

6.3.3. Test data

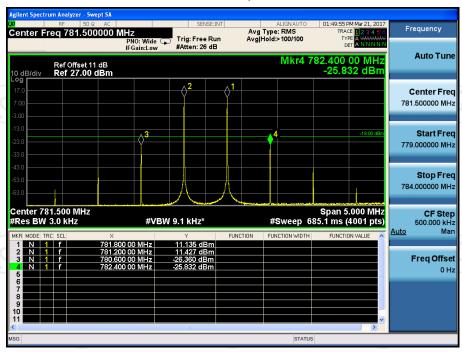
Pre AGC						
Link	Frequency (MHz)	Frequency1 (MHz)	Frequency2 (MHz)	IMD Level [dBm]	IMD Limit [dBm]	Margin (dB)
Uplink	781.5	780.6	782.4	-25.83	-19.00	-6.83
Downlink	751.5	750.6	752.8	-36.49	-19.00	-17.49

AGC+10dB						
Link	Frequency (MHz)	Frequency1 (MHz)	Frequency2 (MHz)	IMD Level [dBm]	IMD Limit [dBm]	Margin (dB)
Uplink	781.5	780.6	782.4	-19.63	-19.00	-0.63
Downlink	751.5	750.6	752.4	-32.37	-19.00	-4.37

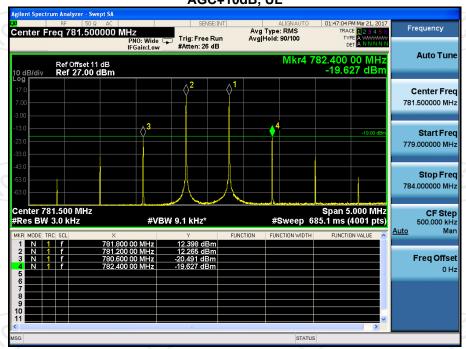


Plot

Pre AGC, UL



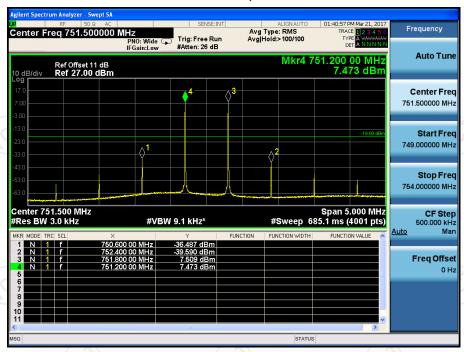
AGC+10dB, UL



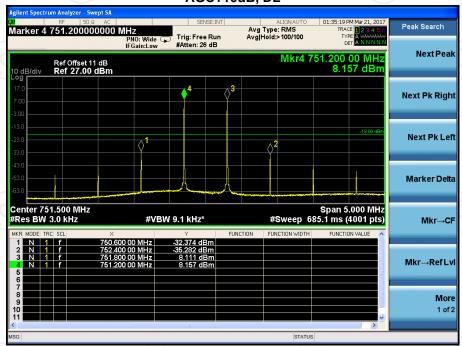




Pre AGC, DL



AGC+10dB, DL







6.4. Out of Band Emission

6.4.1. Test Specification

Test Requirement:	FCC Part20 Section 20.21(e)(8)(i)(E)
Test Method:	KDB935210 D03 Signal Booster Measurement v04
Limit:	-19dBm
Test Setup:	RF Attenuator (if required) Spectrum Analyzer Signal Generator
Test Procedure:	a) Connect the EUT to the test equipment as shown in Set-Up. Begin with the uplink output connected to the spectrum analyzer. b) Configure the signal generator for the appropriate operation for all uplink and downlink bands: i) GSM: 0.2 MHz from upper and lower band edge ii) LTE (5 MHz): 2.5 MHz from upper and lower band edge, except for cellular as follows (only the upper and lower frequencies need to be tested): 824.88 MHz, 845.73 MHz, 836.52 MHz, 848.10 MHz, 869.88 MHz, 890.73 MHz, 881.52 MHz, 893.10 MHz. Note 1: Alternative test modulation types: • CDMA (alternative 1.25 MHz AWGN) • LTE 5 MHz (alternative W-CDMA or 4.1 MHz AWGN) Note 2: For LTE, the signal generator should utilize the uplink and downlink signal types for these modulations in uplink and downlink signal types for these modulations in uplink and downlink signal types for these modulations in uplink and downlink c) Set the signal generator amplitude to the maximum power level prior to AGC similar to the procedures in method of Maximum power d) to f) of power measurement procedure for appropriate modulations. d) Set RBW = measurement bandwidth specified in the applicable rule section for the supported frequency band. e) Set VBW = 3 x RBW. f) Select the RMS (power averaging) detector. g) Sweep time = auto-couple. h) Set the analyzer start frequency to the upper band/block edge frequency plus 300 kHz (when operational frequency is < 1 GHz). i) Trace average at least 100 traces in power averaging (i.e., RMS) mode. j) Use peak marker function to find the maximum power level. k) Capture the spectrum analyzer trace of the power level for inclusion in the test report. l) Increase the signal generator amplitude in 2 dB steps until the maximum input level indicated in 5.4 is reached. Ensure that the EUT maintains compliance with the OOBE limits. m) Reset the analyzer start frequency to the lower band/block edge frequency minus 100 kHz or 1 MHz, as per applicable rule part, and the stop frequency to the lower band/block edge frequency since with the loop



	Report No.: 10111000020
	n) Repeat steps b) through m) for each uplink and downlink
	operational band.
Test Result:	PASS

6.4.2. Test Instruments

Equipment	Manufactur er	Model	Serial Number	Calibration Date	Calibration Due
Signal Generator	Agilent	N5182	MY4707028 2	Aug. 15, 2016	Aug. 11, 2017
Spectrum Analyzer	Agilent	N9020A	MY4910006 0	Aug. 15, 2016	Aug. 11, 2017
Attenuation	AF115A-09- 34	JFW	907763	Aug. 15, 2016	Aug. 11, 2017

Note: The calibration interval of the above test instruments is 12 months and the calibrations are traceable to international system unit (SI).

6.4.3. Test data

Link	Signal Type	Bandedge	Frequency (MHz)	Emission Level [dBm]	Emission Limit [dBm]	Result	
Uplink	GSM	Low	775.979	-28.80			
		Uper	787.003	-27.32		PASS	
	CDMA	Low	775.975	-25.99	1		
		Uper	787.002	-20.80			
	AWGN	Low	776.000	-22.44			
		Uper	787.002	-20.268	10		
Downlink	GSM	Low	745.984	-39.88	-19		
		Uper	757.003	-34.88			
	CDMA	Low	745.973	-44.09			
		Uper	757.002	-38.44			
	AWGN	Low	746.000	-26.63			
		Uper	757.000	-26.57			

Note: The EUT also maintains compliance with the out-of-band emissions limit at input power indicated in section 5.5.



Plot

GSM UL



L-edge



H-edge



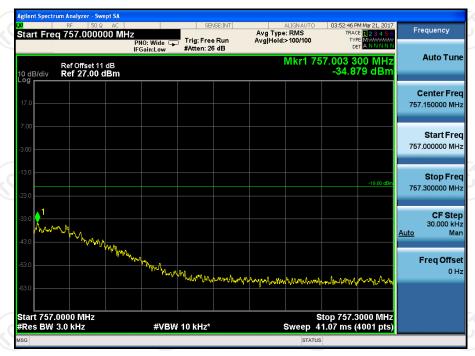


Plot

GSM DL



L-edge



H-edge



Plot

CDMA UL



L-edge

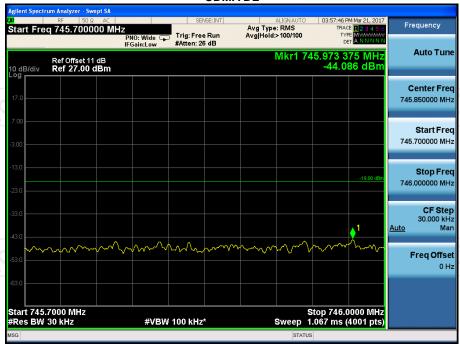


H-edge

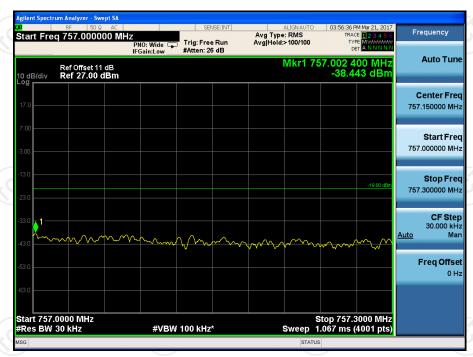


Plot

CDMA DL



L-edge



H-edge



Plot

LTE UL



L-edge



H-edge



Plot

LTE DL



L-edge



H-edge



6.5. Conducted Spurious Emission

6.5.1. Test Specification

Test Requirement:	FCC Part2 Section 1051; FCC Rules Part 27 Subpart C, Section 27.53				
Test Method:	KDB 935210 D03 Signal Booster Measurement V04				
Limit:	 §2.1053, Conducted emissions limit = 43 + 10 log (P) = -13 dBm §27.53(c), For operations in the 746-758 MHz band and the 776-788 MHz band On all frequencies between 763-775 MHz and 793-805 MHz, by a factor not less than 76 + 10 log (P) dB=-46dBm in a 6.25 kHz band segment, for base and fixed stations §27.53(e), For operations in the 746-758 MHz, 775-788 MHz, and 805-806 MHz bands Emissions in the band 1559-1610 MHz shall be limited to -70 dBW(-40dBm)/MHz equivalent isotropically radiated power (EIRP) for wideband signals, and -80 dBW(-50dBm) EIRP for discrete emissions of less than 700 Hz bandwidth. 				
Test Setup:	RF Attenuator (if required) Spectrum Analyzer Signal Generator				
Test Procedure:	a) Connect the EUT to the test equipment as shown in Set-Up. Begin with the uplink output connected to the spectrum analyzer. b) Configure the signal generator for AWGN with a 99% occupied bandwidth of 4.1 MHz operation with a center frequency corresponding to the center of the CMRS band under test. c) Set the signal generator amplitude to the level determined in the power measurement procedure in Maximum power. d) Turn on the signal generator RF output and measure the spurious emission power levels with an appropriate measurement instrument as follows. e) Set RBW = measurement bandwidth specified in the applicable rule section for the operational frequency band under consideration (see Annex A for relevant cross-references). Note that many of the individual rule sections permit the use of a narrower RBW (typically ≥ 1% of the emission bandwidth) to enhance measurement accuracy, but the result must then be integrated over the specified measurement bandwidth. f) Set VBW = 3 X RBW. g) Select the power averaging (RMS) detector. (See above note regarding the use of a peak detector for preliminary measurements.) h) Sweep time = auto-couple. i) Set the analyzer start frequency to the lowest radio frequency signal generated in the equipment, without going below 9 kHz, and the stop frequency to the lower band/block edge frequency minus 100 kHz or 1 MHz, as specified in the applicable rule part. Note that the number of measurement points in each sweep must be ≥ (2 X span/RBW) which may require that the measurement range				



Report No.: TCT170309E018 defined by the start and stop frequencies above be subdivided, depending on the available number of measurement points provided by the spectrum analyzer. Trace average at least 10 traces in power averaging (i.e., RMS) mode. j) Use the peak marker function to identify the highest amplitude level over each measured frequency range Record the frequency and amplitude and capture a plot for inclusion in the test report. k) Reset the analyzer start frequency to the upper band/block edge frequency plus 100 kHz or 1 MHz, as specified in the applicable rule part, and the analyzer stop frequency to 10 times the highest frequency of the fundamental emission. Note that the number of measurement points in each sweep must be ≥ (2 X span/RBW) which may require that the measurement range defined by the start and stop frequencies above be subdivided, depending on the available number of measurement points provided by the spectrum analyzer. I) Use the peak marker function to identify the highest amplitude level over each of the measured frequency ranges. Record the frequency and amplitude and capture a plot for inclusion in the test

m) Repeat steps b) through I) for each supported frequency band of

Test Result:

PASS

operation.

6.5.2. Test Instruments

Equipment	Manufactur er	Model	Serial Number	Calibration Date	Calibration Due
Signal Generator	Agilent	N5182	MY4707028 2	Aug. 15, 2016	Aug. 11, 2017
Spectrum Analyzer	Agilent	N9020A	MY4910006 0	Aug. 15, 2016	Aug. 11, 2017
Attenuation	AF115A-09- 34	JFW	907763	Aug. 15, 2016	Aug. 11, 2017

Note: The calibration interval of the above test instruments is 12 months and the calibrations are traceable to international system unit (SI).

6.5.3. Test data

